## МІНІСТЕРСТВО ОСВІТИ І НАУКИ УКРАЇНИ СУМСЬКИЙ ДЕРЖАВНИЙ УНІВЕРСИТЕТ

## ФІЗИКА, ЕЛЕКТРОНІКА, ЕЛЕКТРОТЕХНІКА

ФЕЕ: 2016

**МАТЕРІАЛИ** та програма

НАУКОВО-ТЕХНІЧНОЇ КОНФЕРЕНЦІЇ

(Суми, 18-22 квітня 2016 року)



Суми Сумський державний університет 2016

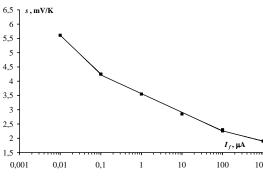
## ФЕЕ:: 2016

## Diode temperature sensors with tunable sensitivity

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We investigated the possibility of using of AlGaInP heterostructures with p-n junction as diode temperature sensors having quasi-linear dependence of the forward voltage drop on the ambient temperature at the fixed direct current. Thus we measured the current-voltage characteristics of the p-n structures in the temperature range 293-550 K. Using the data obtained we calculated the differential current thermal sensitivity of the structures mentioned. A semilogarithmic plot of the thermal sensitivity vs. forward current dependence is presented in the figure. As one can see from the graph plotted the dependence has a characteristic property: there are



three distinct sections in it having different slopes. This means that there are different current transport mechanisms predominate in each section. At the lowest current  $(\sim 10^{-8} - 10^{-7} \text{ A})$  the current transport is dominated tunneling, then one can observe mixed tunnel-1000 recombination

transport mode ( $\sim 10^{-7}$ - $10^{-4}$  A) and at further current rise ( $\geq 10^{-4}$  A) the diode gradually passes into recombination mode with appreciable influence of the series resistance at  $I \geq 10^{-3}$  A.

All of this allows to conclude that it is possible to design temperature sensor based on the AlGaInP p-n heterostructures with tunable thermal sensitivity [1] by changing the magnitude of the forward current through the diode.

1. Yu. M. Shwarts, *Physical fundamentals of the semiconductor devices of extreme electronics*. (Dr. of Sci. Thesis, Kyiv: V. Lashkaryov ISP NASU: 2004).